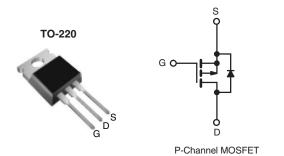




Power MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	- 100			
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = - 10 V	1.2		
Q _g (Max.) (nC)	8.7			
Q _{gs} (nC)	2.2			
Q _{gd} (nC)	4.1			
Configuration	Single			



FEATURES

- Dynamic dV/dt Rating
- · Repetitive Avalanche Rated
- P-Channel
- 175 °C Operating Temperature
- · Fast Switching
- · Ease of Paralleling
- · Simple Drive Requirements
- Lead (Pb)-free Available

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 W. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.

ORDERING INFORMATION		
Package	TO-220	
Load (Dh.) from	IRF9510PbF	
Lead (Pb)-free	SiHF9510-E3	
SnPb	IRF9510	
SHED	SiHF9510	

ABSOLUTE MAXIMUM RATINGS T _C = 25 °C, unless otherwise noted						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	- 100	V	
Gate-Source Voltage			V_{GS}	± 20		
Continuous Drain Current	V _{GS} at - 10 V	T _C = 25 °C	- I _D	- 4.0		
	V _{GS} at - 10 V	T _C = 100 °C		- 2.8	Α	
Pulsed Drain Current ^a			I _{DM}	- 16		
Linear Derating Factor				0.29	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	200	mJ	
Repetitive Avalanche Currenta			I _{AR}	- 4.0	Α	
Repetitive Avalanche Energy ^a			E _{AR}	4.3	mJ	
Maximum Power Dissipation	T _C = 25 °C		P_{D}	43	W	
Peak Diode Recovery dV/dtc			dV/dt	- 5.5	V/ns	
Operating Junction and Storage Temperature Range			T_J,T_stg	- 55 to + 175	°C	
Soldering Recommendations (Peak Temperature)	for 10 s			300 ^d	7	
Manatia a Tayana	6-32 or M3 screw			10	lbf ⋅ in	
Mounting Torque				1.1	N · m	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. V_{DD} = 25 V, starting T_J = 25 °C, L = 18 mH, R_G = 25 Ω , I_{AS} = 4.0 A (see fig. 12).
- c. $I_{SD} \le$ 4.0 A, dI/dt \le 75 A/ μ s, $V_{DD} \le V_{DS}$, $T_J \le$ 175 °C.
- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply

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THERMAL RESISTANCE RATINGS				
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	62	
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.50	-	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	3.5	

PARAMETER	SYMBOL	TEST	MIN.	TYP.	MAX.	UNIT	
Static					•		
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = - 250 μA		- 100	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	to 25 °C, I _D = - 1 mA	-	- 0.091	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V$	' _{GS} , I _D = - 250 μA	- 2.0	-	- 4.0	V
Gate-Source Leakage	I _{GSS}	V	_{GS} = ± 20 V	-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}		V _{DS} = - 100 V, V _{GS} = 0 V V _{DS} = - 80 V, V _{GS} = 0 V, T _J = 150 °C		-	- 100 - 500	μΑ
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = - 10 V	I _D = - 2.4 A ^b	-	-	1.2	Ω
Forward Transconductance	9 _{fs}	V _{DS} = - 8	50 V, I _D = - 2.4 A ^b	1.0	-	-	S
Dynamic					•		
Input Capacitance	C _{iss}	V - 0 V		-	200	-	
Output Capacitance	C _{oss}	V	$V_{GS} = 0 \text{ V},$ $V_{DS} = -25 \text{ V},$		94	-	pF
Reverse Transfer Capacitance	C _{rss}	f = 1.0 MHz, see fig. 5		-	18	-	
Total Gate Charge	Qg		$V_{GS} = -10 \text{ V}$ $I_D = -4.0 \text{ A}, V_{DS} = -80 \text{ V},$ see fig. 6 and 13 ^b	-	-	8.7	nC
Gate-Source Charge	Q _{gs}	V _{GS} = - 10 V		-	-	2.2	
Gate-Drain Charge	Q _{gd}			-	-	4.1	
Turn-On Delay Time	t _{d(on)}			-	10	-	
Rise Time	t _r	V _{DD} = -	V _{DD} = - 50 V, I _D = - 4.0 A,		27	-	- ns
Turn-Off Delay Time	t _{d(off)}	$R_G = 24 \Omega$, $R_D = 11 \Omega$, see fig. 10^b		-	15	-	
Fall Time	t _f			-	17	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	
Internal Source Inductance	L _S			-	7.5	-	nH
Drain-Source Body Diode Characteristic	s				•		
Continuous Source-Drain Diode Current	I _S	MOSFET symb	MOSFET symbol showing the		-	- 4.0	A
Pulsed Diode Forward Current ^a	I _{SM}	integral reverse p - n junction diode		ı	-	- 16	, A
Body Diode Voltage	V_{SD}	$T_J = 25 ^{\circ}\text{C}, I_S = -4.0 \text{A}, V_{GS} = 0 \text{V}^{\text{b}}$		-	-	- 5.5	V
Body Diode Reverse Recovery Time	t _{rr}	$T_J = 25 ^{\circ}\text{C}, I_F = -4.0 \text{A}, \text{dI/dt} = 100 \text{A/}\mu\text{s}^b$		ı	82	160	ns
Body Diode Reverse Recovery Charge	Q _{rr}				0.15	0.30	μC
Forward Turn-On Time	t _{on}	Intrinsic tur	n-on time is negligible (turn	on is dor	minated by	y L _S and	L _D)

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 μ s; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

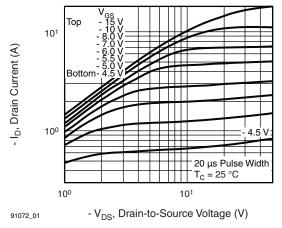


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

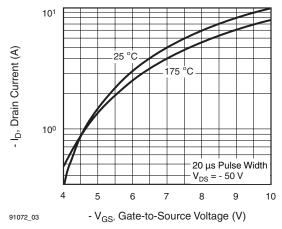


Fig. 3 - Typical Transfer Characteristics

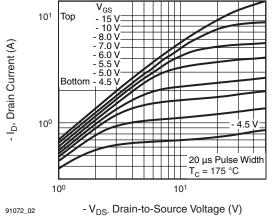


Fig. 2 - Typical Output Characteristics, T_C = 175 $^{\circ}C$

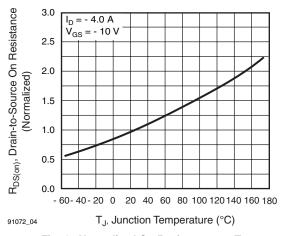


Fig. 4 - Normalized On-Resistance vs. Temperature

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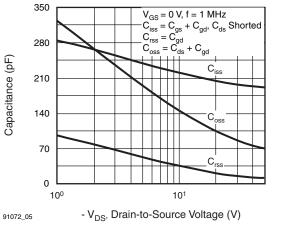


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

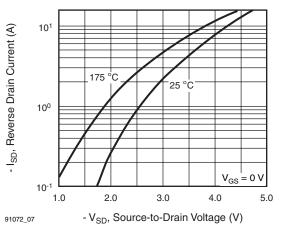


Fig. 7 - Typical Source-Drain Diode Forward Voltage

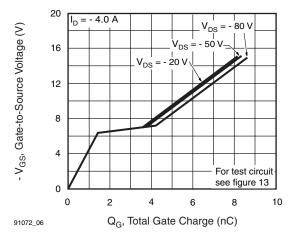


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

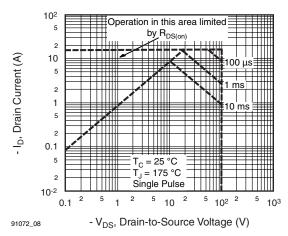
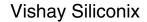


Fig. 8 - Maximum Safe Operating Area





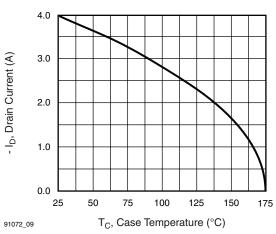


Fig. 9 - Maximum Drain Current vs. Case Temperature

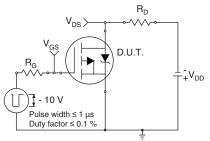


Fig. 10a - Switching Time Test Circuit

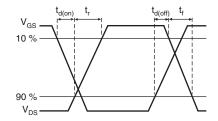


Fig. 10b - Switching Time Waveforms

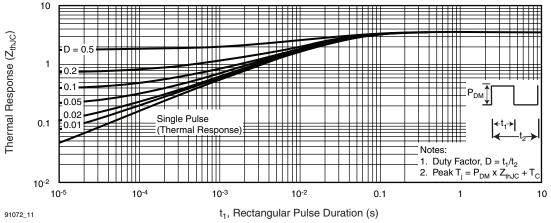


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

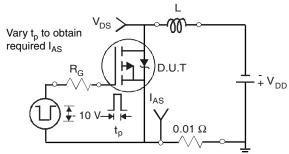


Fig. 12a - Unclamped Inductive Test Circuit

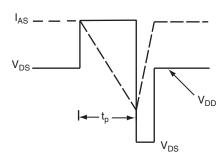


Fig. 12b - Unclamped Inductive Waveforms



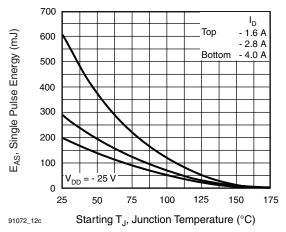


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

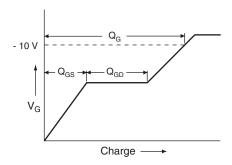


Fig. 13a - Basic Gate Charge Waveform

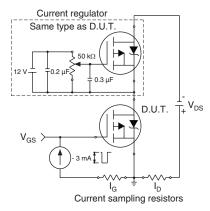
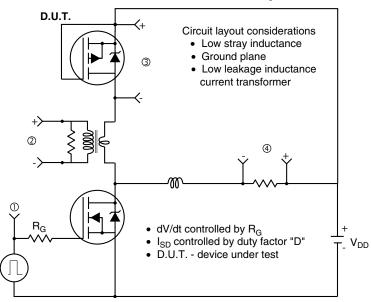


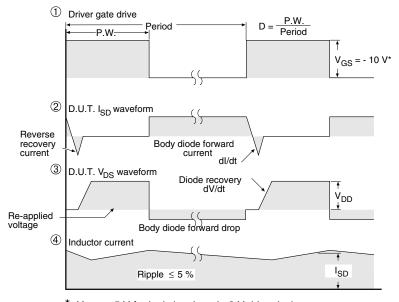
Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



• Compliment N-Channel of D.U.T. for driver



* V_{GS} = - 5 V for logic level and - 3 V drive devices

Fig. 14 - For P-Channel

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